



CMOS Low Power Dual 2:1 Mux/Demux

USB 2.0 (480 Mbps)/USB 1.1 (12 Mbps)

ADG772

FEATURES

- USB 2.0 (480 Mbps) and USB 1.1 (12 Mbps) signal switching compliant**
- Tiny 10-lead 1.6 mm × 1.3 mm mini LFCSP package and 12-lead 3 mm × 3 mm LFCSP package**
- 2.7 V to 3.6 V single-supply operation**
- Typical power consumption: <0.1 µW**
- RoHS compliant**

APPLICATIONS

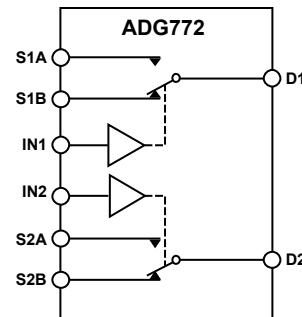
- USB 2.0 signal switching circuits**
- Cellular phones**
- PDAs**
- MP3 players**
- Battery-powered systems**
- Headphone switching**
- Audio and video signal routing**
- Communications systems**

GENERAL DESCRIPTION

The ADG772 is a low voltage, CMOS device that contains two independently selectable single-pole, double throw (SPDT) switches. It is designed as a general-purpose switch and can be used for routing both USB 1.1 and USB 2.0 signals.

This device offers a data rate of 1260 Mbps, making the part suitable for high frequency data switching. Each switch conducts equally well in both directions when on and has an input signal range that extends to the supplies. The ADG772 exhibits break-before-make switching action.

The ADG772 comes in a 12-lead LFCSP, and a 10-lead mini LFCSP. These packages make the ADG772 the ideal solution for space-constrained applications.



SWITCHES SHOWN FOR A LOGIC 0 INPUT

06092.001

Figure 1.

PRODUCT HIGHLIGHTS

1. 1.6 mm × 1.3 mm mini LFCSP package.
2. USB 1.1 (12 Mbps) and USB 2.0 (480 Mbps) compliant.
3. Single 2.7 V to 3.6 V operation.
4. RoHS compliant.

Rev. 0

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REVISION HISTORY

8/07—Revision 0: Initial Version

ADG772**ABSOLUTE MAXIMUM RATINGS**

$T_A = 25^\circ\text{C}$, unless otherwise noted.

Table 2.

Parameter	Rating
V_{DD} to GND	-0.3 V to +4.6 V
Analog Inputs ¹ , Digital Inputs	-0.3 V to $V_{DD} + 0.3$ V or 10 mA, whichever occurs first
Peak Current, Pin S1A, Pin S2A, Pin D1, or Pin D2	100 mA (pulsed at 1 ms, 10% duty cycle max)
Continuous Current, Pin S1A, Pin S2A, Pin D1, or Pin D2	30 mA
Operating Temperature Industrial Range (B version)	-40°C to +85°C
Storage Temperature Range	-65°C to +150°C
Junction Temperature	150°C
10-Lead Mini LFCSP (4-Layer Board)	131.6°C/W
θ_{JA} Thermal Impedance	
12-Lead LFCSP (4-Layer Board)	61°C/W
θ_{JA} Thermal Impedance	
Pb-Free Temperature, Soldering, IR Reflow	260(+0/-5)°C
Peak Temperature	
Time at Peak Temperature	10 sec to 40 sec

¹ Overvoltages at the IN1, IN2, S1A, S2A, D1, or D2 pins are clamped by internal diodes. Current should be limited to the maximum ratings given.

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Only one absolute maximum rating may be applied at any one time.

ESD CAUTION

ESD (electrostatic discharge) sensitive device.
Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

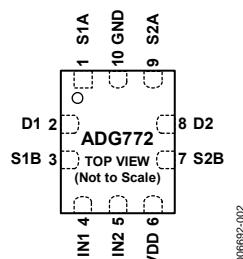


Figure 2. 10-Lead Mini LFCSP Pin Configuration

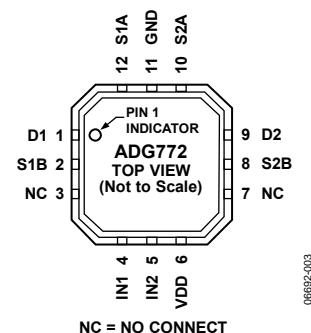


Figure 3. 12-Lead LFCSP Pin Configuration

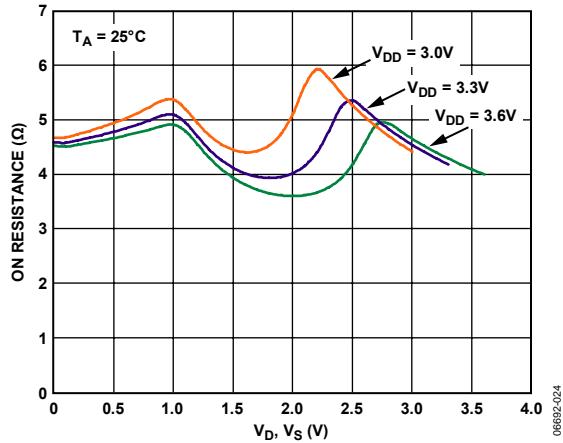
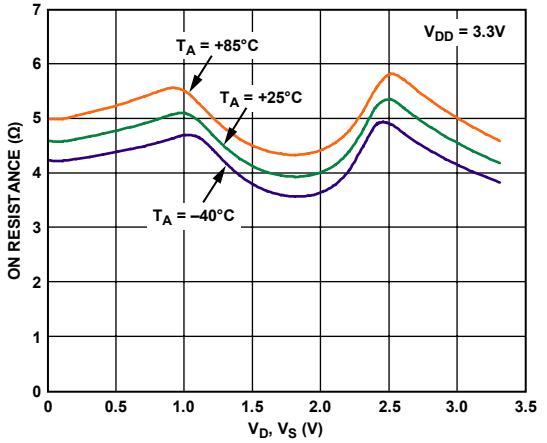
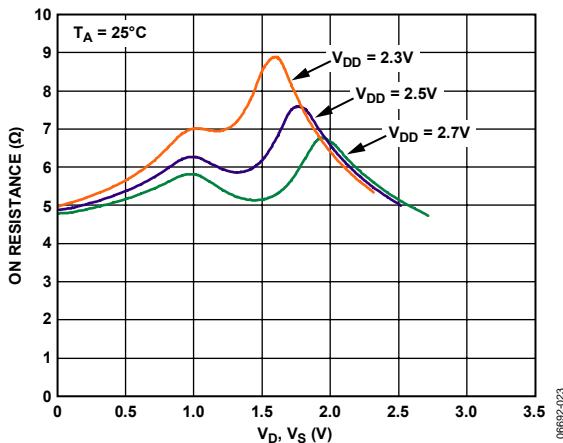
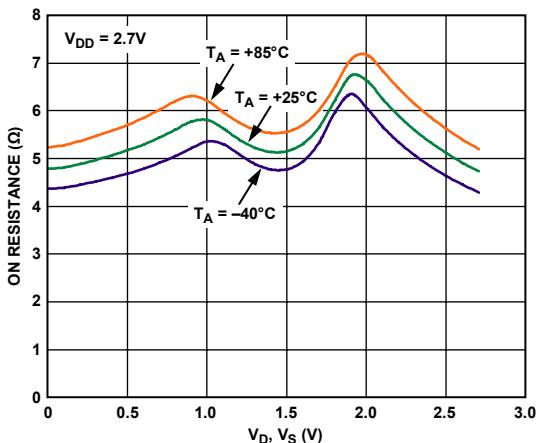
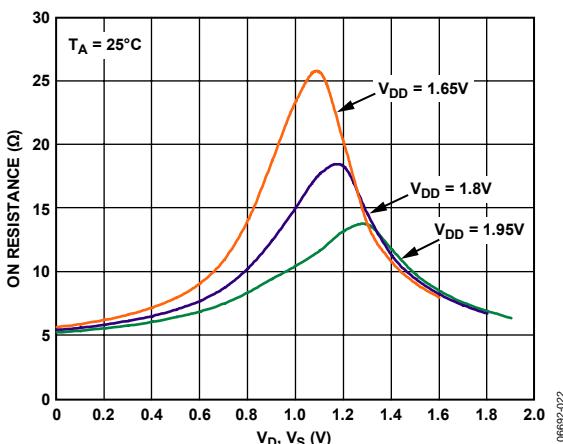
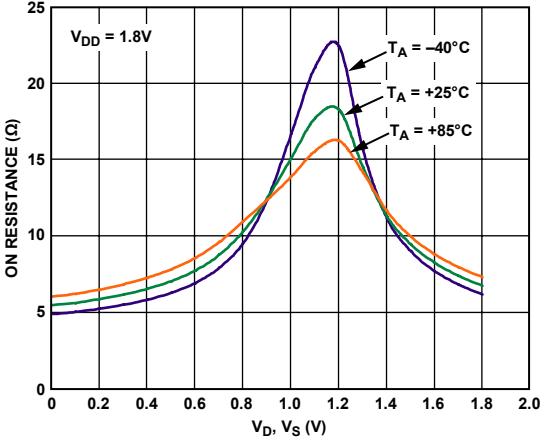
Table 3. Pin Function Descriptions

10-Lead Mini LFCSP	12-Lead LFCSP	Mnemonic	Description
1	12	S1A	Source Terminal. Can be an input or an output.
2	1	D1	Drain Terminal. Can be an input or an output.
3	2	S1B	Source Terminal. Can be an input or an output.
4	4	IN1	Logic Control Input. Controls Switch S1A/S1B—D1.
5	5	IN2	Logic Control Input. Controls Switch S2A/S2B—D2.
6	6	VDD	Most Positive Power Supply Potential.
7	8	S2B	Source Terminal. Can be an input or an output.
8	9	D2	Drain Terminal. Can be an input or an output.
9	10	S2A	Source Terminal. Can be an input or an output.
10	11	GND	Ground (0 V) Reference.
N/A	3, 7	NC	No Connect.

TRUTH TABLE

Table 4.

Logic (IN1/IN2)	Switch A (S1A or S2A)	Switch B (S1B or S2B)
0	Off	On
1	On	Off

ADG772**TYPICAL PERFORMANCE CHARACTERISTICS**Figure 4. On Resistance vs. V_D (V_S) $V_{DD} = 3.0\text{ V}$ to 3.6 V Figure 7. On Resistance vs. V_D (V_S) for Different Temperature, $V_{DD} = 3.3\text{ V}$ Figure 5. On Resistance vs. V_D (V_S) $V_{DD} = 2.5\text{ V} \pm 0.2\text{ V}$ Figure 8. On Resistance vs. V_D (V_S) for Different Temperature, $V_{DD} = 2.7\text{ V}$ Figure 6. On Resistance vs. V_D (V_S) $V_{DD} = 1.8\text{ V} \pm 0.15\text{ V}$ Figure 9. On Resistance vs. V_D (V_S) for Different Temperatures, $V_{DD} = 1.8\text{ V}$

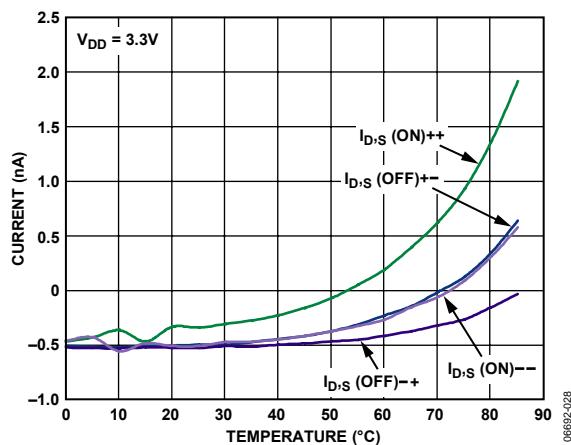
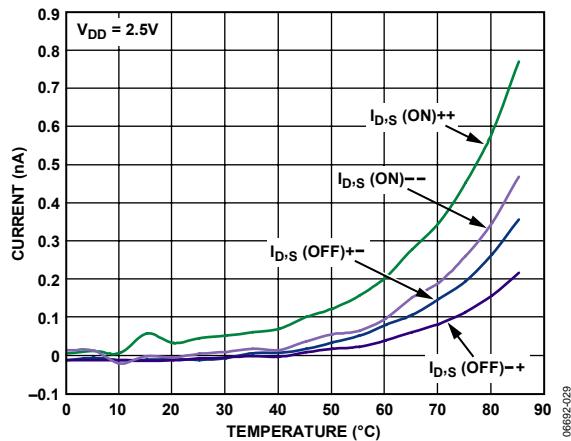
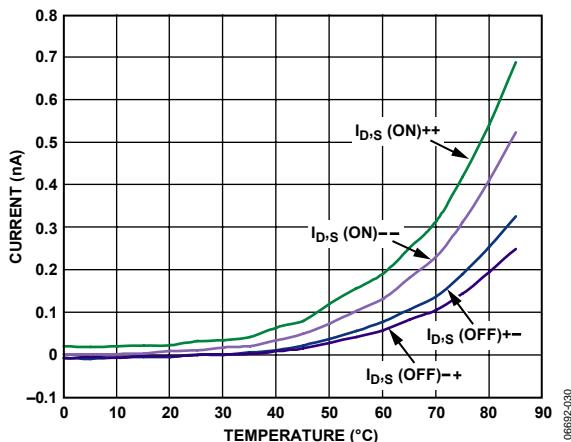
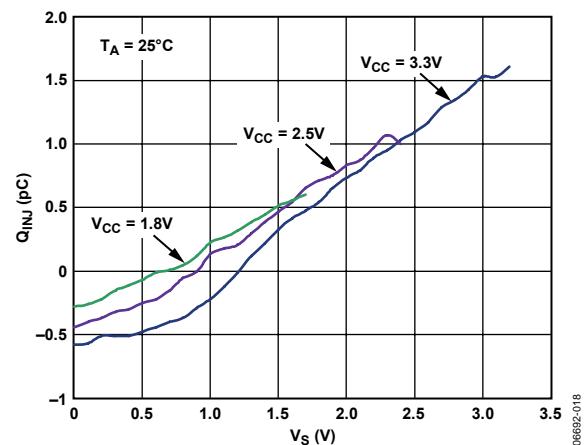
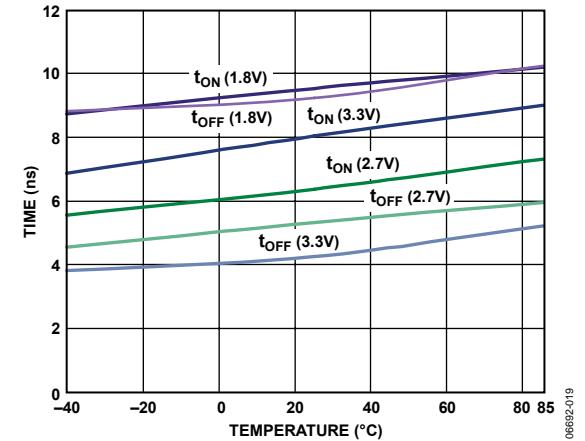
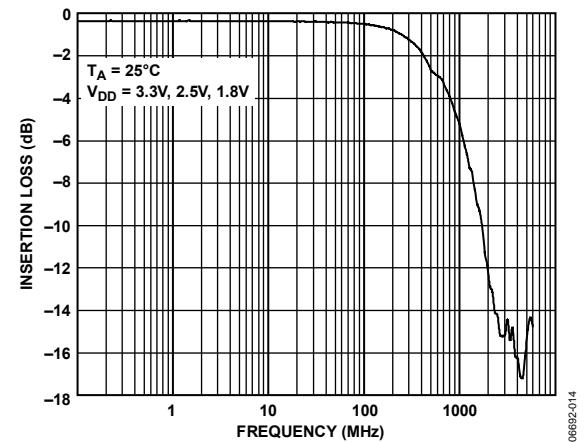
Figure 10. Leakage Current vs. Temperature, $V_{DD} = 3.3\text{ V}$ Figure 11. Leakage Current vs. Temperature, $V_{DD} = 2.5\text{ V}$ Figure 12. Leakage Current vs. Temperature, $V_{DD} = 1.8\text{ V}$ 

Figure 13. Charge Injection vs. Source Voltage

Figure 14. t_{ON}/t_{OFF} Times vs. Temperature

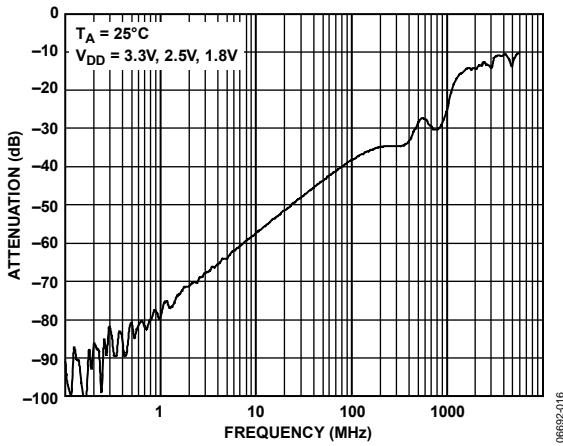
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Figure 16. Off Isolation vs. Frequency

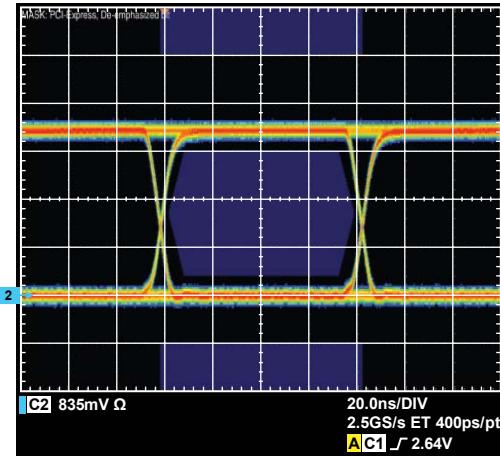


Figure 19. USB 1.1 Eye Diagram

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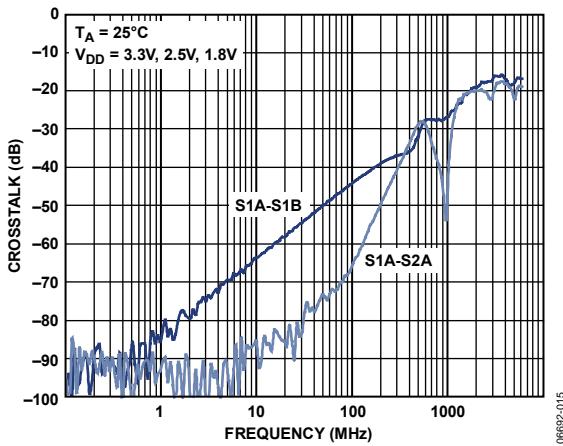


Figure 17. Crosstalk vs. Frequency

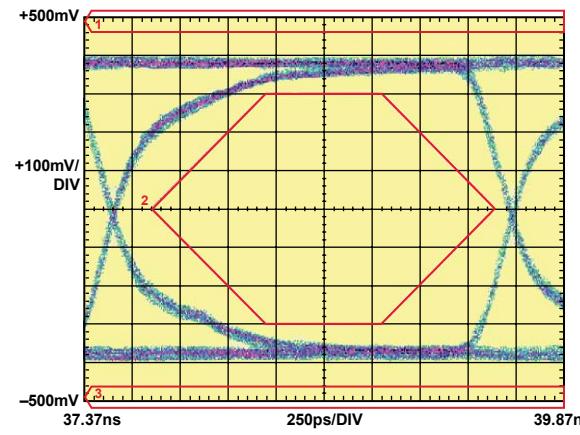


Figure 20. USB 2.0 Eye Diagram

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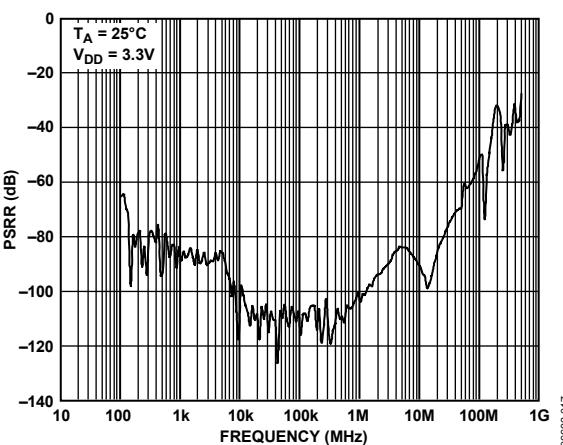


Figure 18. PSRR vs. Frequency

TEST CIRCUITS

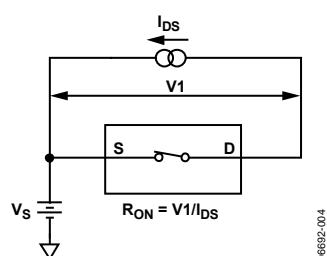


Figure 21. On Resistance

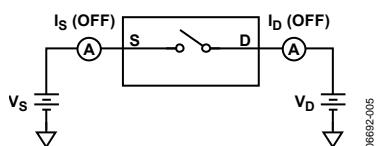


Figure 22. Off Leakage

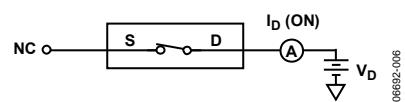


Figure 23. On Leakage

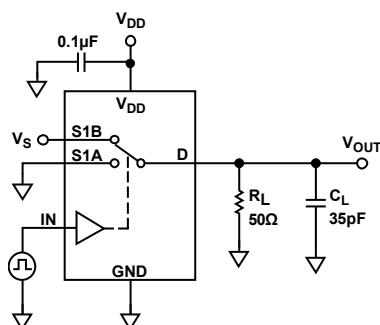
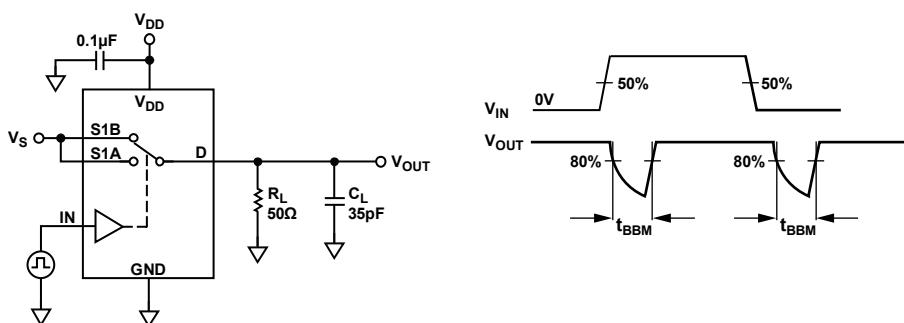
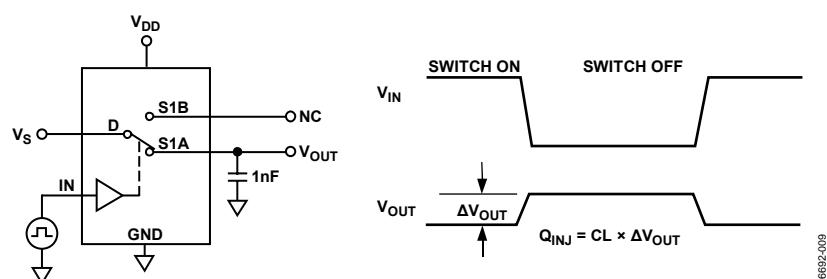
Figure 24. Switching Times, t_{ON} , t_{OFF} Figure 25. Break-Before-Make Time Delay, t_{BBM} 

Figure 26. Charge Injection

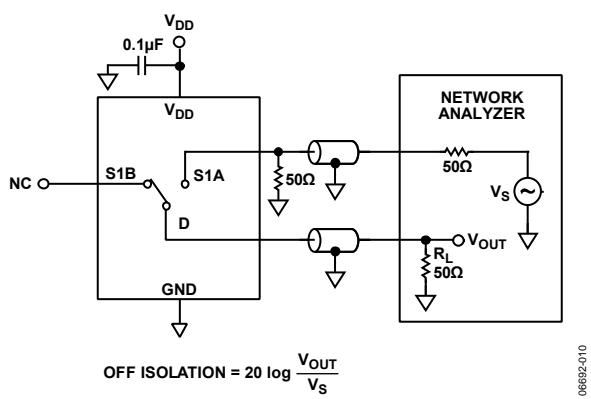
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Figure 27. Off Isolation

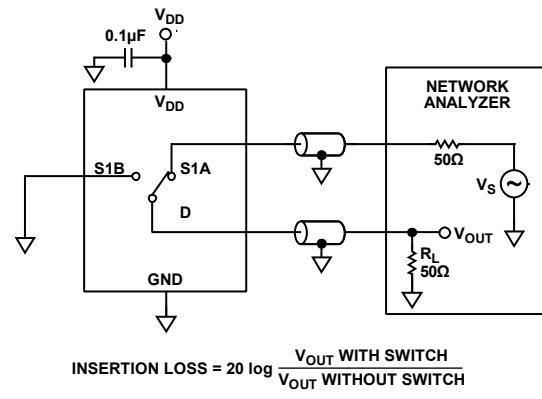


Figure 29. Channel-to-Channel Crosstalk (S1A-S1B)

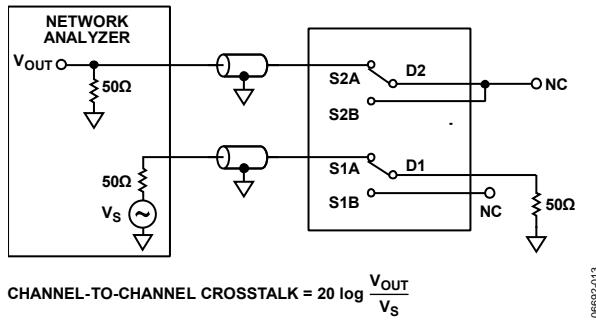


Figure 28. Channel-to-Channel Crosstalk (S1A-S2A)

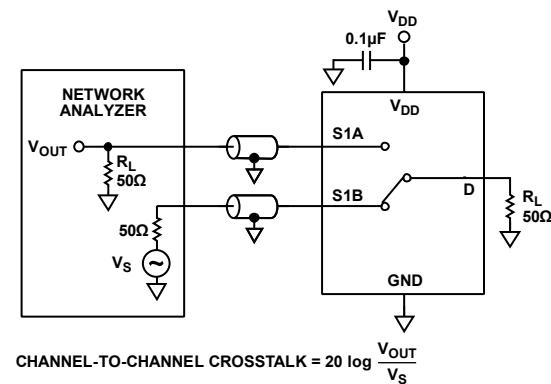
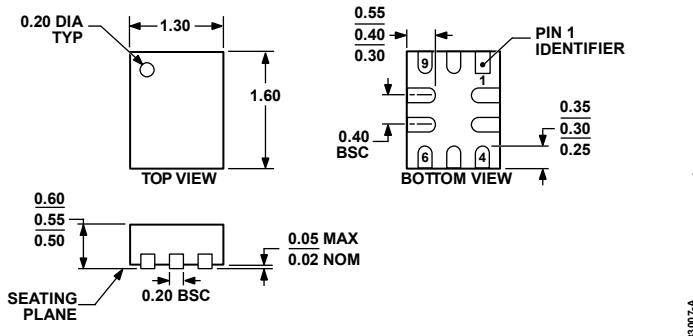


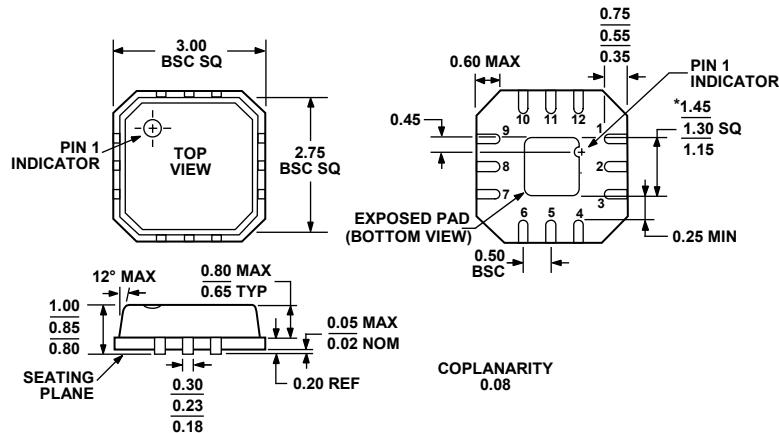
Figure 30. Bandwidth

TERMINOLOGY

I_{DD}	C _{IN}
Positive supply current.	Digital input capacitance.
V_D (V_S)	t_{ON}
Analog voltage on Terminal D and Terminal S.	Delay time between the 50% and 90% points of the digital input and switch on condition.
R_{ON}	t_{OFF}
Ohmic resistance between Terminal D and Terminal S.	Delay time between the 50% and 90% points of the digital input and switch off condition.
R_{FLAT} (On)	t_{BBM}
The difference between the maximum and minimum values of on resistance as measured on the switch.	On or off time measured between the 80% points of both switches when switching from one to another.
ΔR_{ON}	Charge Injection
On resistance match between any two channels.	Measure of the glitch impulse transferred from the digital input to the analog output during on/off switching.
I_S (Off)	Off Isolation
Source leakage current with the switch off.	Measure of unwanted signal coupling through an off switch.
I_D (Off)	Crosstalk
Drain leakage current with the switch off.	Measure of unwanted signal that is coupled from one channel to another as a result of parasitic capacitance.
I_D, I_S (On)	-3 dB Bandwidth
Channel leakage current with the switch on.	Frequency at which the output is attenuated by 3 dB.
V_{INL}	On Response
Maximum input voltage for Logic 0.	Frequency response of the on switch.
V_{INH}	Insertion Loss
Minimum input voltage for Logic 1.	The loss due to the on resistance of the switch.
I_{INL} (I_{INH})	THD + N
Input current of the digital input.	Ratio of the harmonics amplitude plus noise of a signal to the fundamental.
C_S (Off)	T_{SKEW}
Off switch source capacitance. Measured with reference to ground.	The measure of the variation in propagation delay between each channel.
C_D (Off)	
Off switch drain capacitance. Measured with reference to ground.	
C_D, C_S (On)	
On switch capacitance. Measured with reference to ground.	

ADG772**OUTLINE DIMENSIONS**

*Figure 31. 10-Lead Mini Lead Frame Chip Scale Package (LFCSP_UQ)
1.30 mm × 1.60 mm Body, Ultra Thin Quad
(CP-10-10)*
Dimensions shown in millimeters



*COMPLIANT TO JEDEC STANDARDS MO-220-VEED-1
EXCEPT FOR EXPOSED PAD DIMENSION.

*Figure 32. 12-Lead Lead Frame Chip Scale Package (LFCSP_VQ)
3 mm × 3 mm Body, Very Thin Quad
(CP-12-1)*
Dimensions shown in millimeters

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option	Branding
ADG772BCPZ-1REEL ¹	-40°C to +85°C	12-Lead Lead Frame Chip Scale Package (LFCSP_VQ)	CP-12-1	S2P
ADG772BCPZ-REEL ¹	-40°C to +85°C	10-Lead Mini Lead Frame Chip Scale Package (LFCSP_UQ)	CP-10-10	B
ADG772BCPZ-REEL7 ¹	-40°C to +85°C	10-Lead Mini Lead Frame Chip Scale Package (LFCSP_UQ)	CP-10-10	B
EVAL-ADG772EBZ ¹	-40°C to +85°C	Evaluation Board		

¹Z = RoHS Compliant Part.